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1. A method for fabricating a semiconductor package comprising:

providing a substrate having a first surface with a die attach area thereon;

depositing a photoimageable mask material on the first surface and on the die attach area;

exposing and developing the mask material to form a mask having an opening on the die attach area;

placing a semiconductor die in the opening; and bonding the die to the die attach area.

- 2. The method of claim 1 further comprising exposing and developing the mask material to form via openings in the mask for bonding solder balls to the substrate.
- 3. The method of claim 1 wherein bonding the die comprises forming an adhesive layer between the die and the substrate.
- 4. A method for fabricating a semiconductor package comprising:

providing a substrate having a first surface;

depositing a photoimageable mask material on the substrate, the mask material substantially covering the first surface;

exposing and developing the mask material to form a mask having an opening which defines a die attach area on the first surface; and

bonding a semiconductor die to the die attach area by forming an adhesive layer between the die and substrate.

5. The method of claim 4 further comprising depositing the mask material on a second surface of the substrate and exposing and developing the mask material to form a second mask on the second surface.

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6. The method of claim 4 further comprising providing the substrate with a plurality of conductors and forming via openings through the mask material to the conductors for bonding solder balls thereto.

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7. A method for fabricating a semiconductor package comprising:

providing a substrate having a first surface and a second surface;

providing a pattern of conductors on the first surface;

forming a first mask on the first surface comprising a plurality of via openings to the conductors;

forming a second mask on the second surface comprising an opening therein defining a die attach area on the substrate; and

attaching a semiconductor die directly to the die attach area.

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- 8. The method of claim 7 further comprising wire bonding the dig to the conductors.
- 9. The method of claim 7 wherein the first mask and the second mask comprise a same photoimageable material.

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10.// A method for fabricating a semiconductor package comprising:

providing a substrate having a first surface and a second surface;

providing a pattern of conductors on the first surface;

providing a die attach area on the second surface; depositing a photoimageable mask material on the first surface and on the conductors;

depositing the photoimageable mask material on the second surface and on the die attach area;

exposing and developing the mask material on the first surface to form a first mask having a plurality of via openings to the conductors;

exposing and developing the mask material on the second surface to form a second mask having an opening to the die attach area; and

attaching a semiconductor die directly to the die attach area.

- 11. The method of claim 10 further comprising providing the substrate with a second opening and wire bonding wires through the second opening to the die and to the conductors.
- 12. The method of claim 10 further comprising encapsulating the die in an encapsulating resin.
- 13. The method of claim 10 further comprising placing solder balls in the via openings and bonding the solder balls to ball bonding pads on the conductors.
- 14. The method of claim 10 further comprising wire bonding the die to the conductors.
- 15. A method for fabricating a semiconductor package comprising:

 providing a substrate having a first surface and a second surface;

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providing a pattern of conductors on the first surface, the conductors comprising a plurality of ball bonding pads;

substantially covering the first surface and the second surface with a photoimageable mask material;

exposing and developing the mask material on the first surface to form a first mask having a plurality of via openings to the ball bonding pads;

exposing and developing the mask material on the second surface to form a second mask having an opening to the substrate defining a die attach area;

attaching a semiconductor die directly to the die attach area; and

placing solder palls in the via openings and bonding the balls to the ball bonding pads.

- 16. The method of claim 15 further comprising providing the conductors with wire bonding pads and wire bonding the die to the wire bonding pads.
- 17. The method of claim 15 wherein the mask material comprises a resist.
- 18. The method of claim 15 wherein attaching the die comprises forming an adhesive layer between the die and substrate.
- 19. The method of claim 15 further comprising encapsulating the die in an encapsulating resin.
- 20. The method of claim 15 wherein the substrate includes a second opening in the die attach area and the die is placed face down on the substrate and wire bonded through the second opening to the conductors.

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- 21. A semiconductor lead frame comprising:
- a substrate having a first surface and a second surface;
- a plurality of conductors formed on the first surface;
- a first mask formed on the first surface comprising a plurality of via openings to the conductors; and
- a second mask formed on the second surface comprising an opening defining a die attach area on the substrate.
- 10 22. The lead frame of claim 21 further comprising a plurality of die bonding pads on the conductors aligned with the via openings.
 - 23. The lead frame of claim 21 further comprising a second opening through the substrate for wire bonding the die to the conductors.
 - 24. A substrate for fabricating a semiconductor package comprising:
 - a plurality of conductors formed on a first surface of the substrate, the conductors comprising a plurality of ball bonding pads;
 - a first mask formed on the first surface comprising a plurality of via openings to the ball bonding pads; and
 - a second mask substantially covering a second surface of the substrate, and including an opening there through defining a die attach area on the substrate.
 - 25. The substrate of claim 24 further comprising a semiconductor die adhesively bonded to the die attach area.
 - 26. The substrate of claim 25 wherein the die attach area has an outline corresponding to an outline of the die.

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 2∇ . A substrate for a semiconductor package comprising:

a first surface on the substrate and an opposing second surface on the substrate, the second surface having a die attach area thereon;

a plurality of conductors formed on the first surface, each conductor comprising a wire bonding pad and a ball bonding pad;

a first mask formed on the first surface comprising a plurality of via openings aligned with selected ball bonding pads on the conductors and a first opening exposing selected wire bonding pads on the conductors; and

a second mask substantially covering the second surface and including a second opening there through to the die attach area.

28. The substrate of claim 27 wherein the substrate comprises a third opening there through for wire bonding a die to the wire bonding pads.

29. The substrate of claim 27 wherein the first mask and the second mask comprise a photoimageable dielectric material.

30. A semiconductor package comprising:

a substrate having a first surface and a second surface;

a plurality of conductors formed on the first surface, the conductors comprising a plurality of ball bonding pads;

a first mask formed on the first surface comprising a plurality of via openings to the ball bonding pads

a second mask substantially covering the second surface and including an opening there through defining a die attach area on the substrate;

a semiconductor die attached to the die attach area in electrical communication with the conductors; and

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a plurality of solder balls placed in the via openings and bonded to the ball bonding pads.

- 31. The package of claim 30 further comprising an encapsulating resin on the substrate encapsulating the die.
 - 32. The package of claim 30 wherein the die is wire bonded to the conductors.
 - 33. The package of claim 33 further comprising an adhesive layer attaching the die to the die attach area.
 - 34. A semiconductor package comprising:
 - a substrate comprising a first surface and an opposing second surface having a die attach area thereon;
 - a plurality of conductors formed on the first surface, each conductor comprising a wire bonding pad and a ball bonding pad;
 - a first mask formed on the first surface comprising a plurality of via openings aligned with selected ball bonding pads on the conductors and a first opening exposing selected wire bonding pads on the conductors;
 - a second mask substantially covering the second surface and including a second opening there through to the die attach area;
 - a semiconductor die adhesively bonded to the die attach area and wire bonded to the conductors; and
 - an encapsulating resin formed on the die and substrate.
- 35. The package of claim 34 further comprising a third opening in the substrate for wire bonding the die to the conductors.

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36. The package of claim 35 wherein the die is bonded face down to the die attach area.

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